



DEFENSE LOGISTICS AGENCY
LAND AND MARITIME
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

October 31, 2014

Mr. Edgar Usman
NJ Met
1240 Main Ave.
Clifton, NJ 07011

Dear Mr. Usman:

Re: MIL-STD-883, MIL-STD-750, Commercial Laboratory Suitability for QTSL Program, FSC 5962, 5961; 15-028818; Control Number: 044328

Based on the results of the DLA Land and Maritime audit conducted on August 26-27, 2014, your facility is considered suitably equipped to perform electrical testing as listed in the Enclosure below, and QTSL testing in accordance to the requirements of AS6081.

Your laboratory is to maintain a record for all testing and a summary must be submitted annually to DLA Land and Maritime-VQ which will include the following as a minimum:

- a. Military part number, SMD, or 883 identification
- b. Date code
- c. Quantity tested
- d. Number of devices pass/fail
- e. Manufacturer
- f. Manufacturer's lot number
- g. Test method(s)/condition(s)
- h. Date test completed
- i. Qualification test report number, as applicable
- j. Self-audit reports with deficiencies and corrective actions

The standard reporting period is from 1 January through 31 December and due by 1 March of each year.

NJ Met shall notify the qualifying activity immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on products utilizing the test methods on the attached enclosure. Failure to provide prior notification may be grounds for removal from DLA Land and Maritime's Commercial Lab Suitability Listing.

This laboratory suitability is valid subject to the conditions as stated in DoD 4120.24M. This laboratory suitability is valid until withdrawn by DLA Land and Maritime-VQ. Any deviation to test methods or condition(s) listed herein must be approved by the qualifying activity.

If you have any questions, please contact Mr. Ryan Michael at 614-692-7527.

Sincerely,

RAYMOND L. KOLONCHUK
Chief
Electronic Devices Branch

Visit us on the web at: http://www.dsec.dla.mil/offices/sourcing_and_qualification/

Enclosure to DLA LAND AND MARITIME-VQE-15-028818

<u>TEST</u>	<u>METHOD/CONDITIO N</u>	<u>Location</u>
Radiological (X-RAY)	AS6081 paragraph 4.2.6.4.4	NJ Met 1240 Main Ave. Clifton, NJ 07011
Lead Finish Evaluation (XRF)	AS6081 paragraph 4.2.6.4.5	Same as above
Remarking and Resurfacing	AS6081 paragraph 4.2.6.4.3	Same as above
Decapsulation	AS6081 paragraph 4.2.6.4.6	Same as above
FSC 5962 Electrical Test*	FSC 5962 Limited Electrical Test per Criteria and Provisions for QTSL Booklet 3.1.3	Same as above
Breakdown voltage, collector to base (BVCBO)*	MIL-STD-750 TM 3001	Same as above
Breakdown voltage, collector to emitter (BVCEO)*	MIL-STD-750 TM 3011	Same as above
Breakdown voltage, collector to base (BVCBO)*	MIL-STD-750 TM 3026	Same as above
Collector to emitter cutoff current (ICBO)*	MIL-STD-750 TM 3041	Same as above
Emitter to base cutoff current (IEBO)*	MIL-STD-750 TM 3061	Same as above
Base emitter voltage (saturated or Non-saturated) (VBE(sat) VBE(on))*	MIL-STD-750 TM 3066	Same as above
Saturation voltage (VCE(sat))*	MIL-STD-750 TM 3071	Same as above
Breakdown voltage gate to source (BVGSS)*	MIL-STD-750 TM 3401	Same as above
Gate to source voltage (VGS)*	MIL-STD-750 TM 3403	Same as above
MOSFET threshold voltage (VTH)*	MIL-STD-750 TM 3404	Same as above
Drain to source on state voltage (VOS)*	MIL-STD-750 TM 3405	Same as above
Breakdown voltage drain to source (BVDSS)*	MIL-STD-750 TM 3407	Same as above
Gate reverse current (IGSS)*	MIL-STD-750 TM 3411	Same as above
Drain reverse current (IDSS)*	MIL-STD-750 TM 3415	Same as above
Static drain to source on state resistance (RDS)*	MIL-STD-750 TM 3421	Same as above
Capacitance*	MIL-STD-750 TM 4001	Same as above
Forward Voltage*	MIL-STD-750 TM 4011	Same as above
Reverse Leakage Current*	MIL-STD-750 TM 4016	Same as above
Breakdown Voltage (Diode)*	MIL-STD-750 TM 4021	Same as above
Breakdown Voltage for Regulator and Reference Diodes*	MIL-STD-750 TM 4022	Same as above

Small Signal Reverse Breakdown Impedance*	MIL-STD-750 TM 4051	Same as above
Thermal Resistance of Diodes*	MIL-STD-750 TM 4081	Same as above
Holding current (IH)*	MIL-STD-750 TM 4201	Same as above
Forward blocking current (IAKF)*	MIL-STD-750 TM 4206	Same as above
Reverse blocking current (IAKR)*	MIL-STD-750 TM 4211	Same as above
Gate-trigger voltage (VGT)*	MIL-STD-750 TM 4221	Same as above
Forward on voltage (Von)*	MIL-STD-750 TM 4226	Same as above

*Room temperature testing only